Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/759,183	MATSUO, MIE	
Examiner	Art Unit	
Ben P. Sandvik	2826	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	774	4/4/2005	BPS
257	758	4/4/2005	BPS
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR